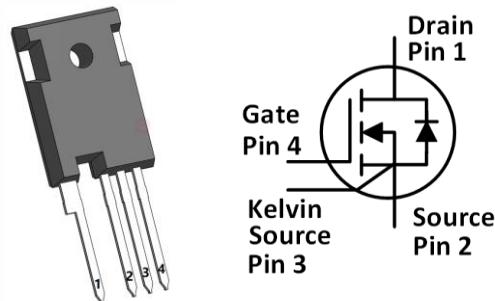


IV2Q12040T4Z – 1200V 40mΩ Gen2 Automotive SiC MOSFET

Features

- 2nd Generation SiC MOSFET Technology with +15~+18V gate drive
- High blocking voltage with low on-resistance
- High speed switching with low capacitance
- 175°C operating junction temperature capability
- Ultra fast and robust intrinsic body diode
- Kelvin gate input easing driver circuit design
- AEC-Q101 qualified

Outline:

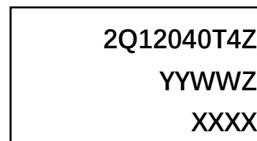


TO247-4

Applications

- EV chargers and OBCs
- Solar boosters
- Automotive compressor inverters
- AC/DC power supplies

Marking Diagram:



2Q12040T4Z= Specific Device Code
 YY = Year
 WW = Work Week
 Z = Assembly Location
 XXXX = Lot Traceability

Absolute Maximum Ratings ($T_c=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
V_{DS}	Drain-Source voltage	1200	V	$V_{GS}=0\text{V}$, $I_D=100\mu\text{A}$	
V_{GSmax} (Transient)	Maximum transient voltage	-10 to 23	V	Duty cycle<1%, and pulse width<200ns	
V_{GSon}	Recommended turn-on voltage	15 to 18	V		
V_{GSooff}	Recommended turn-off voltage	-5 to -2	V	Typical -3.5V	
I_D	Drain current (continuous)	65	A	$V_{GS}=18\text{V}$, $T_c=25^\circ\text{C}$	Fig. 23
		48	A	$V_{GS}=18\text{V}$, $T_c=100^\circ\text{C}$	
I_{DM}	Drain current (pulsed)	162	A	Pulse width limited by SOA and dynamic $R_{\theta(0-C)}$	Fig. 25, 26
I_{SM}	Body diode current (pulsed)	162	A	Pulse width limited by SOA and dynamic $R_{\theta(0-C)}$	Fig. 25, 26
P_{TOT}	Total power dissipation	375	W	$T_c=25^\circ\text{C}$	Fig. 24
T_{stg}	Storage temperature range	-55 to 175	°C		
T_J	Operating junction temperature	-55 to 175	°C		
T_L	Solder Temperature	260	°C	wave soldering only allowed at leads, 1.6mm from case for 10 s	

Thermal Data

Symbol	Parameter	Value	Unit	Note
$R_{\theta(0-C)}$	Thermal Resistance from Junction to Case	0.4	°C/W	Fig. 25

Electrical Characteristics ($T_c=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value			Unit	Test Conditions	Note		
		Min.	Typ.	Max.					
I_{DSS}	Zero gate voltage drain current		5	100	μA	$V_{DS}=1200\text{V}, V_{GS}=0\text{V}$			
I_{GSS}	Gate leakage current			± 100	nA	$V_{DS}=0\text{V}, V_{GS}=-5\text{~}20\text{V}$			
V_{TH}	Gate threshold voltage	1.8	2.8	4.5	V	$V_{GS}=V_{DS}, I_D=9\text{mA}$	Fig. 8, 9		
			2.1			$V_{GS}=V_{DS}, I_D=9\text{mA}$ $@ T_J=175^\circ\text{C}$			
R_{ON}	Static drain-source on-resistance		40	52	$\text{m}\Omega$	$V_{GS}=18\text{V}, I_D=20\text{A}$ $@ T_J=25^\circ\text{C}$	Fig. 4, 5, 6, 7		
			75		$\text{m}\Omega$	$V_{GS}=18\text{V}, I_D=20\text{A}$ $@ T_J=175^\circ\text{C}$			
			50	65	$\text{m}\Omega$	$V_{GS}=15\text{V}, I_D=20\text{A}$ $@ T_J=25^\circ\text{C}$			
			80		$\text{m}\Omega$	$V_{GS}=15\text{V}, I_D=20\text{A}$ $@ T_J=175^\circ\text{C}$			
C_{iss}	Input capacitance		2160		pF	$V_{DS}=800\text{V}, V_{GS}=0\text{V},$ $f=1\text{MHz}, V_{AC}=25\text{mV}$	Fig. 16		
C_{oss}	Output capacitance		100		pF				
C_{rss}	Reverse transfer capacitance		5.8		pF				
E_{oss}	C_{oss} stored energy		40		μJ				
Q_g	Total gate charge		110		nC	$V_{DS}=800\text{V}, I_D=30\text{A},$ $V_{GS}=-3\text{ to }18\text{V}$	Fig. 18		
Q_{gs}	Gate-source charge		25		nC				
Q_{gd}	Gate-drain charge		59		nC				
R_g	Gate input resistance		2.1		Ω				
E_{ON}	Turn-on switching energy		446.3		μJ	$V_{DS}=800\text{V}, I_D=30\text{A},$ $V_{GS}=-3.5\text{ to }18\text{V},$ $R_{G(ext)}=3.3\Omega,$ $L=200\mu\text{H}$ $T_J=25^\circ\text{C}$	Fig. 19, 20		
E_{OFF}	Turn-off switching energy		70.0		μJ				
$t_{d(on)}$	Turn-on delay time		9.6		ns				
t_r	Rise time		22.1						
$t_{d(off)}$	Turn-off delay time		19.3						
t_f	Fall time		10.5						
E_{ON}	Turn-on switching energy		644.4		μJ	$V_{DS}=800\text{V}, I_D=30\text{A},$ $V_{GS}=-3.5\text{ to }18\text{V},$ $R_{G(ext)}=3.3\Omega, L=200\mu\text{H}$ $T_J=175^\circ\text{C}$	Fig. 22		
E_{OFF}	Turn-off switching energy		73.8		μJ				

Reverse Diode Characteristics ($T_c=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value			Unit	Test Conditions	Note
		Min.	Typ.	Max.			
V_{SD}	Diode forward voltage		4.2		V	$I_{SD}=20\text{A}, V_{GS}=0\text{V}$	Fig. 10, 11, 12
			4.0		V	$I_{SD}=20\text{A}, V_{GS}=0\text{V}, T_j=175^\circ\text{C}$	
I_s	Diode forward current (continuous)			63	A	$V_{GS}=-2\text{V}, T_c=25^\circ\text{C}$	
				36	A	$V_{GS}=-2\text{V}, T_c=100^\circ\text{C}$	
t_{rr}	Reverse recovery time		42.0		ns	$V_{GS}=-3.5\text{V}/+18\text{V}, I_{SD}=30\text{A}, V_R=800\text{V}, R_{G(ext)}=10\Omega L=200\mu\text{H}$ $dI/dt=3000\text{A}/\mu\text{s}$	
Q_{rr}	Reverse recovery charge		198.1		nC		
I_{RRM}	Peak reverse recovery current		17.4		A		

Typical Performance (curves)

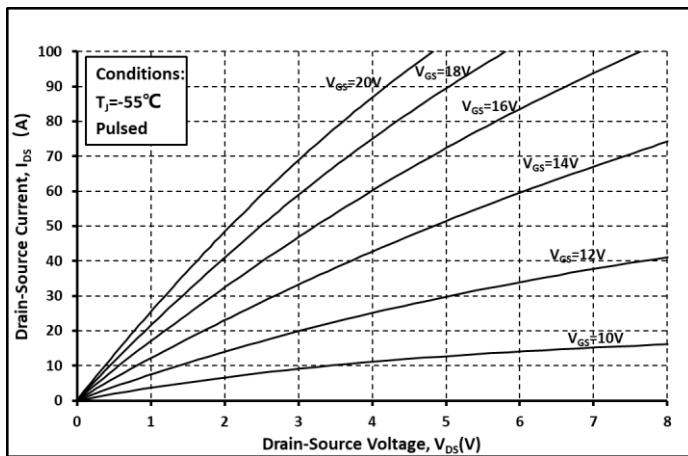


Fig. 1 Output Curve @ $T_j = -55^\circ\text{C}$

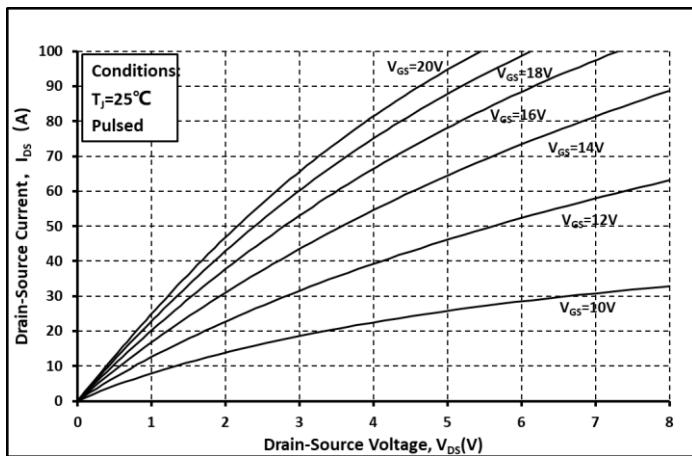


Fig. 2 Output Curve @ $T_j = 25^\circ\text{C}$

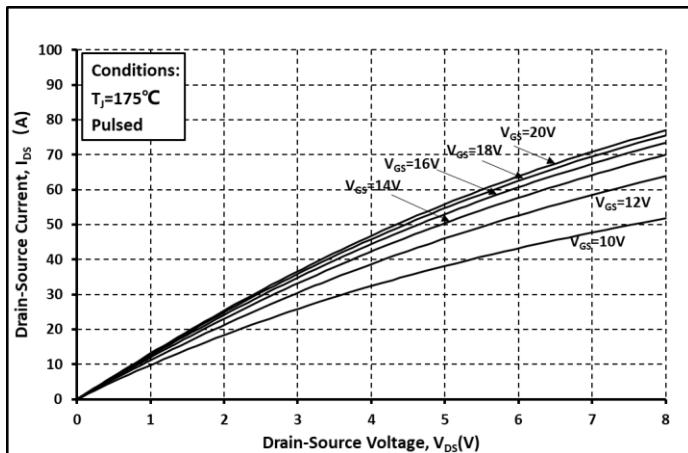


Fig. 3 Output Curve @ $T_j = 175^\circ\text{C}$

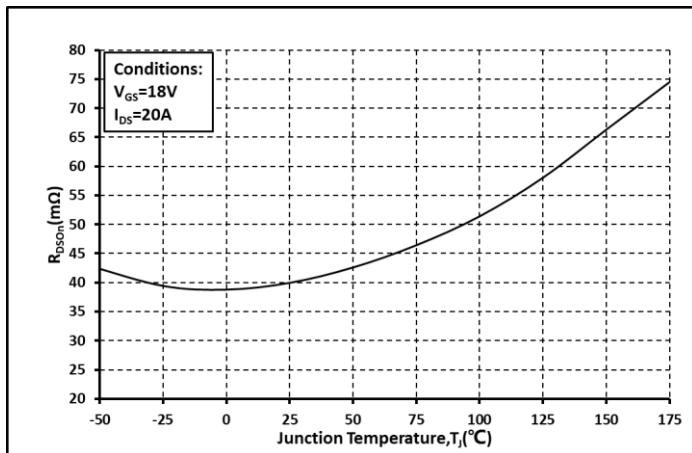


Fig. 4 Ron vs. Temperature

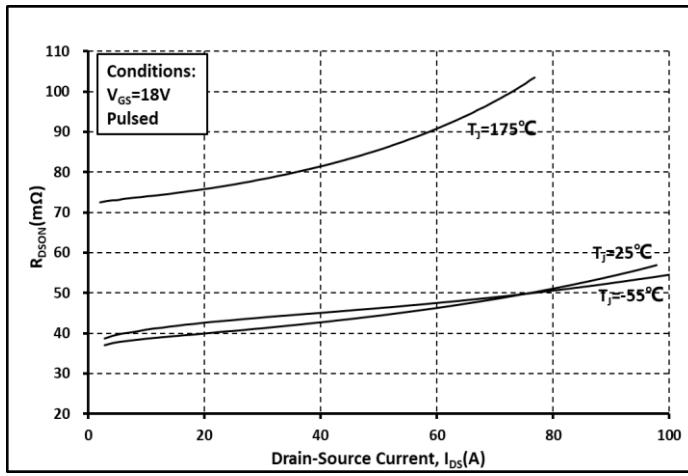


Fig. 5 Ron vs. I_{DS} @ Various Temperature

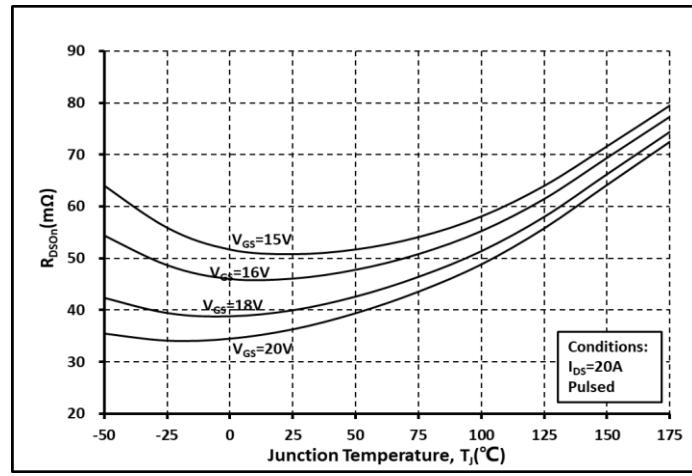


Fig. 6 Ron vs. Temperature @ Various V_{GS}

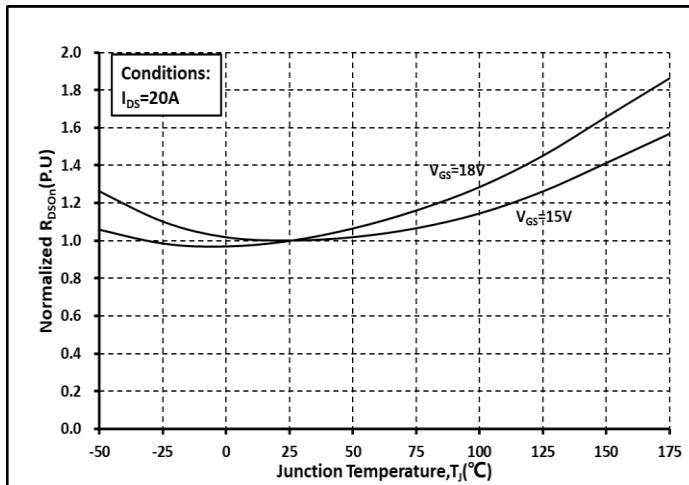


Fig. 7 Normalized $R_{DS(on)}$ vs. Temperature

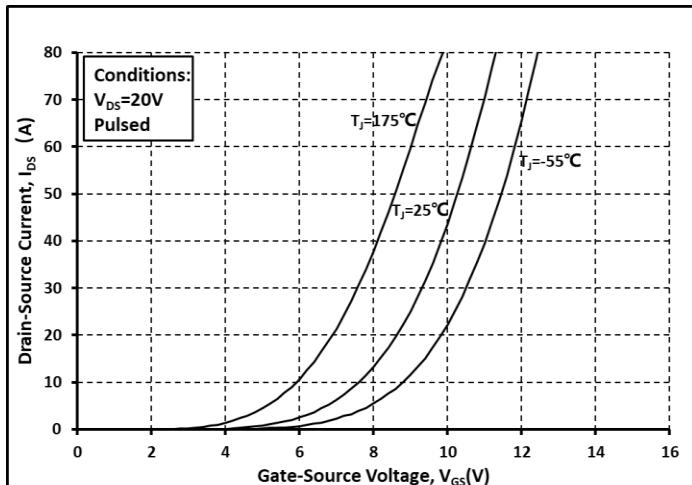


Fig. 8 Transfer Curves @ Various Temperatures

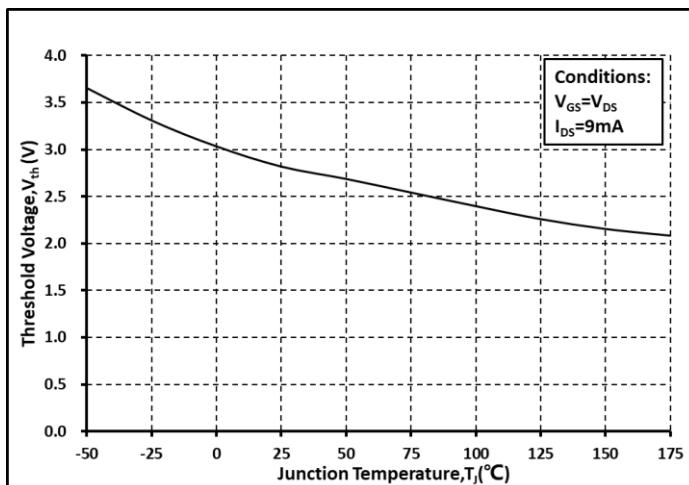


Fig. 9 Threshold Voltage vs. Temperature

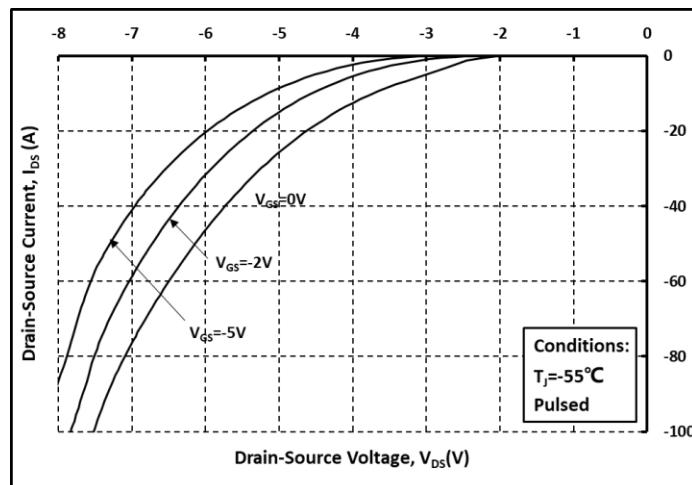


Fig. 10 Body Diode curves @ $T_J = -55^\circ C$

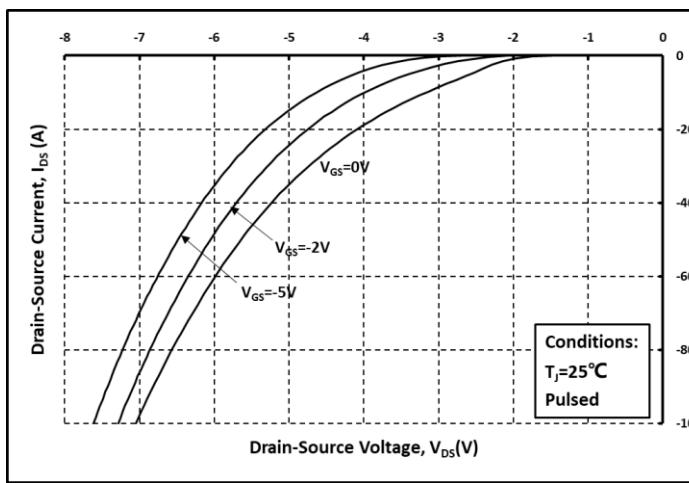


Fig. 11 Body Diode curves @ $T_J = 25^\circ C$

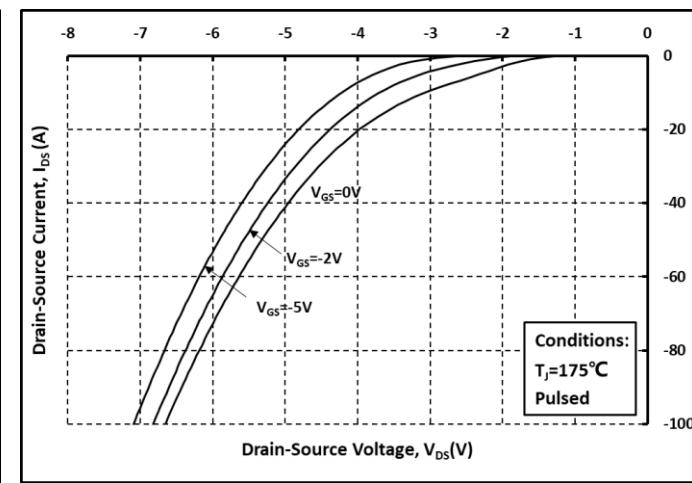


Fig. 12 Body Diode curves @ $T_J = 175^\circ C$

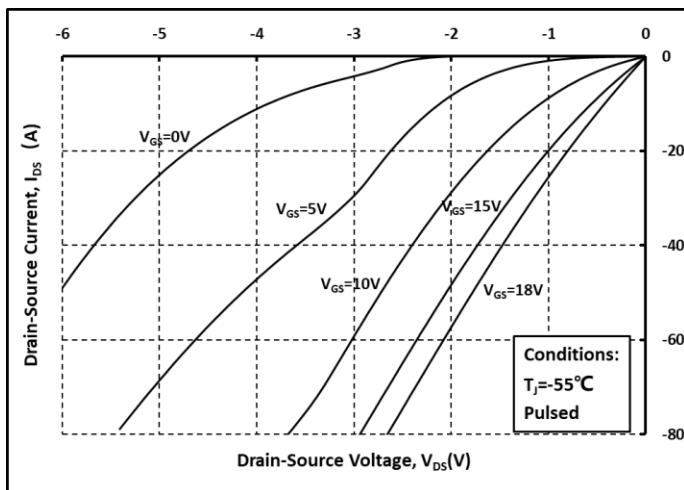


Fig. 13 3rd Quadrant curves @ $T_j = -55^\circ\text{C}$

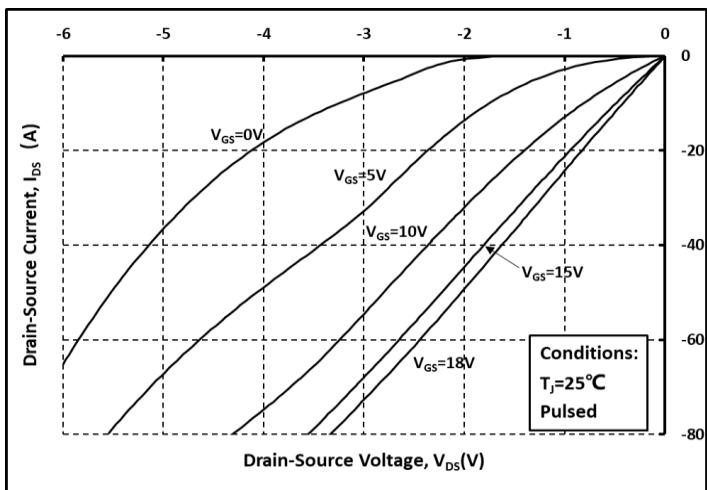


Fig. 14 3rd Quadrant curves @ $T_j = 25^\circ\text{C}$

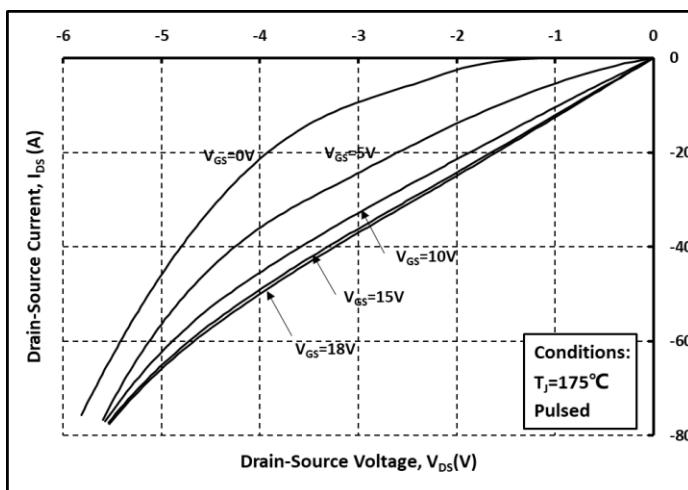


Fig. 15 3rd Quadrant curves @ $T_j = 175^\circ\text{C}$

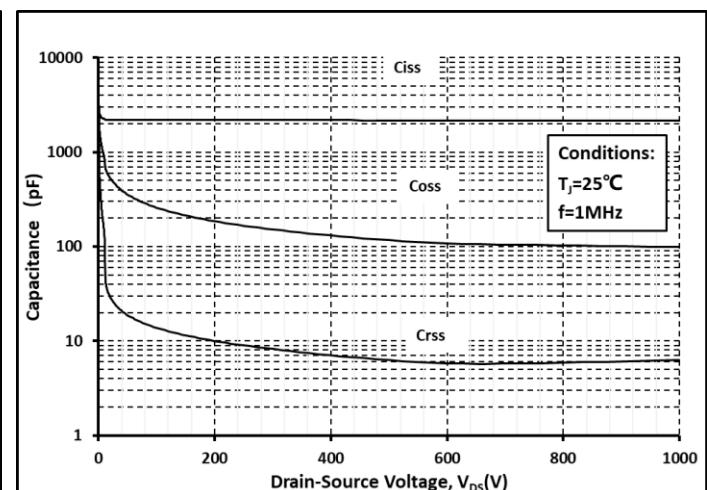


Fig. 16 Capacitance vs. V_{DS}

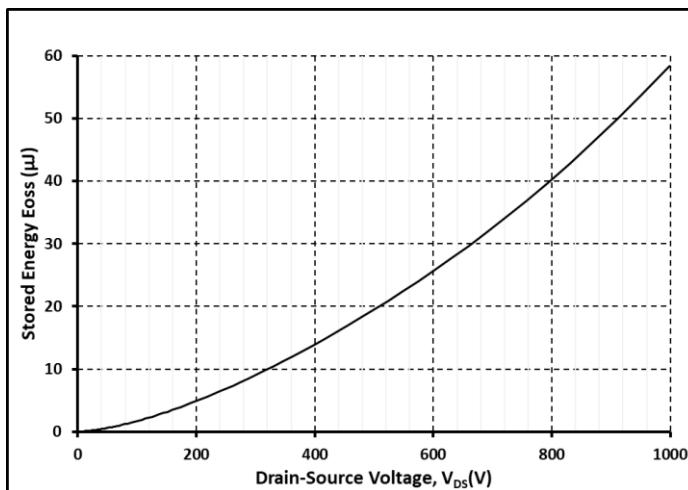


Fig. 17 Output Capacitor Stored Energy

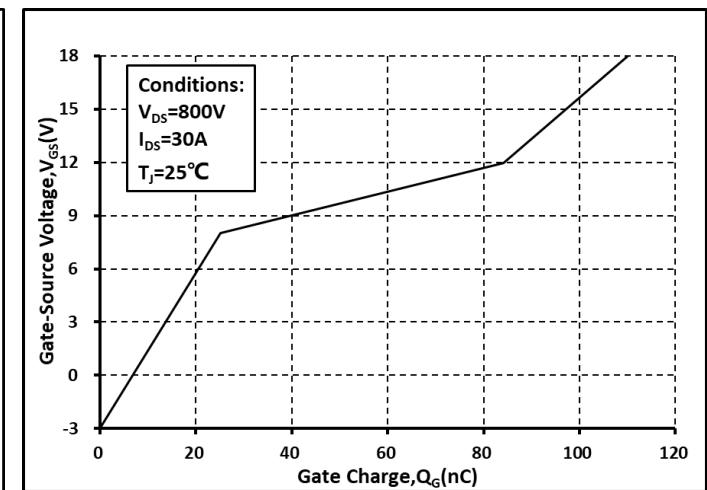


Fig. 18 Gate Charge Characteristics

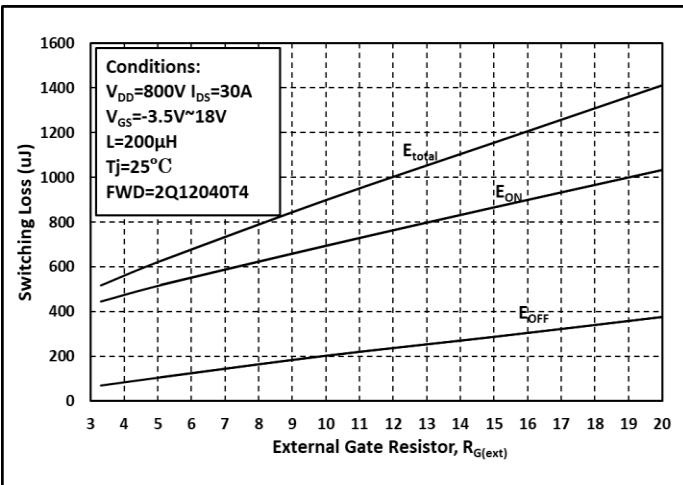


Fig. 19 Switching Energy vs. $R_{G(\text{ext})}$

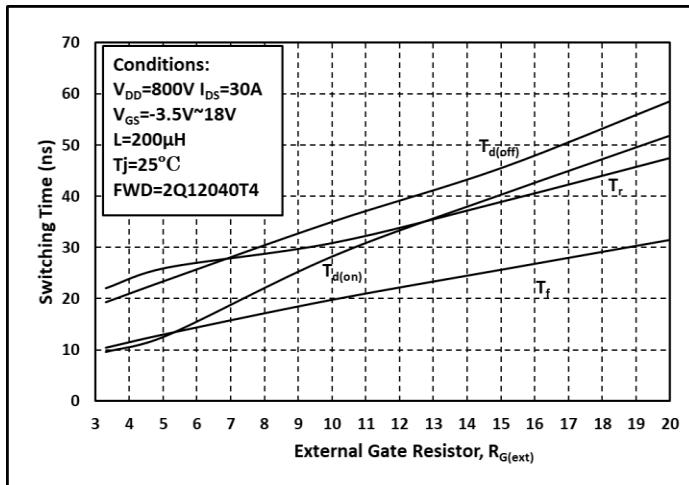


Fig. 20 Switching Times vs. $R_{G(\text{ext})}$

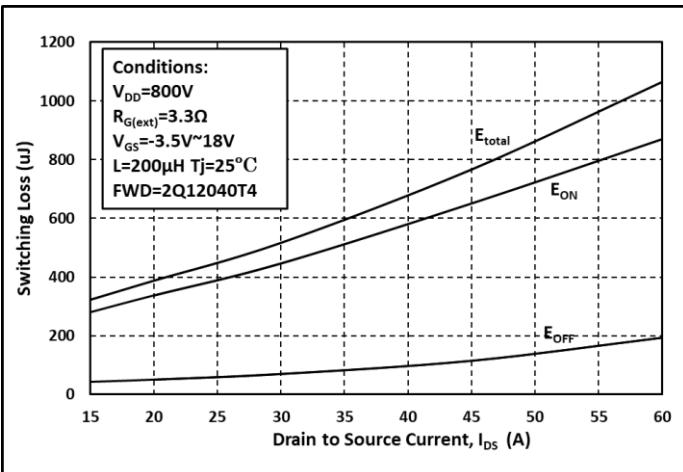


Fig. 21 Switching Energy vs. I_{DS}

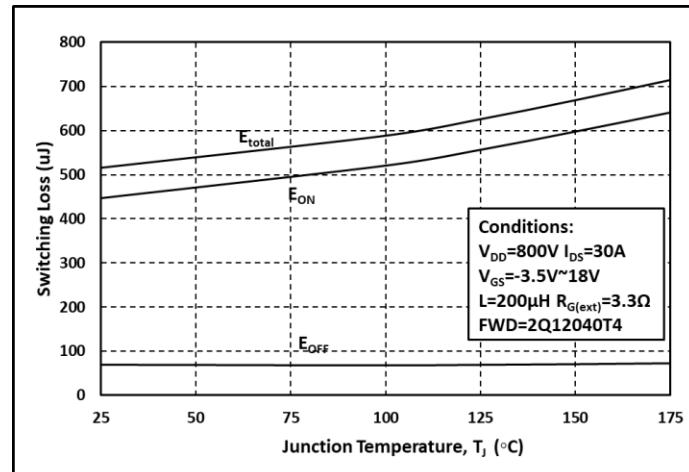


Fig. 22 Switching Energy vs. Temperature

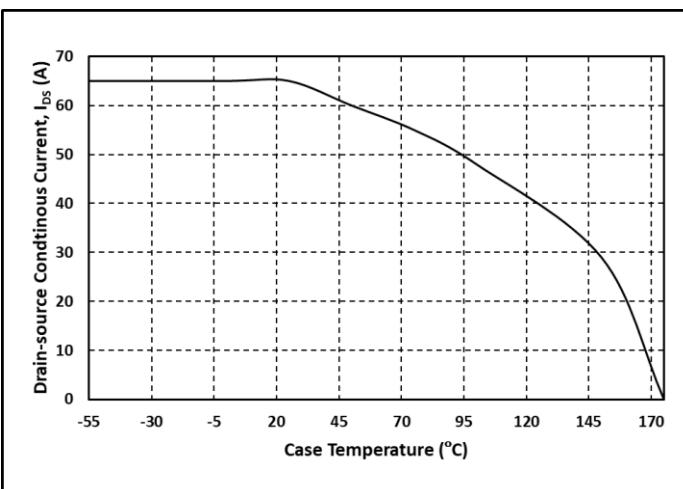


Fig. 23 Continuous Drain Current vs. Case Temperature

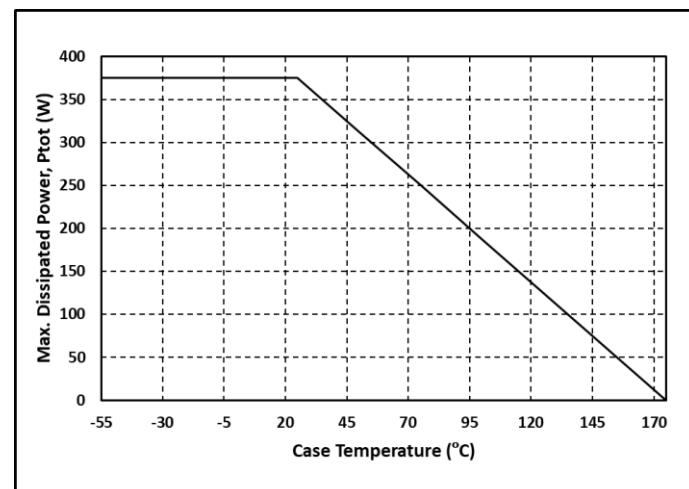


Fig. 24 Max. Power Dissipation Derating vs. Case Temperature

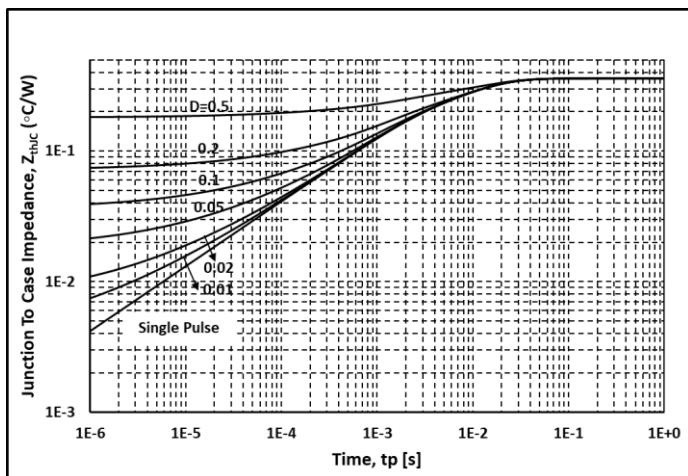


Fig. 25 Thermal impedance

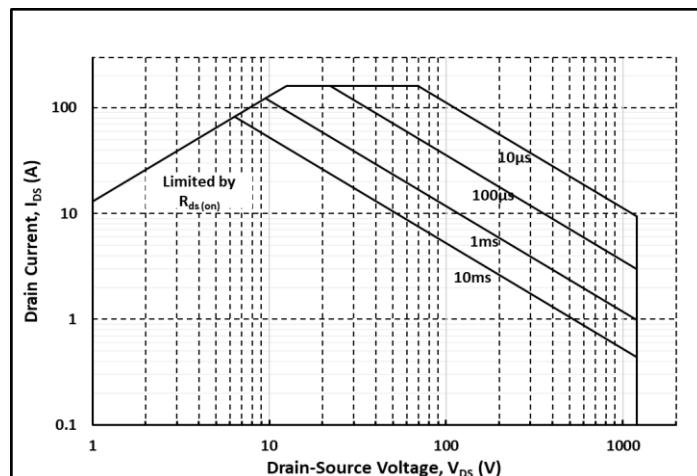
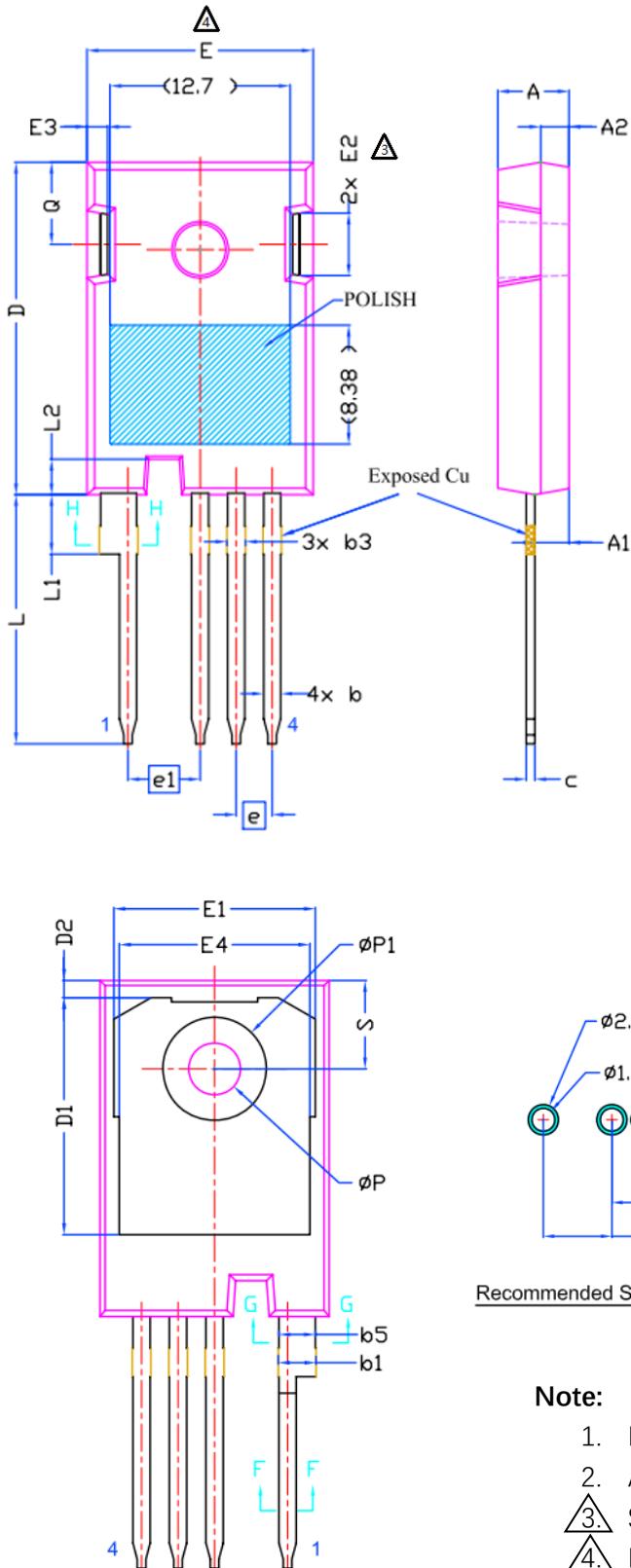
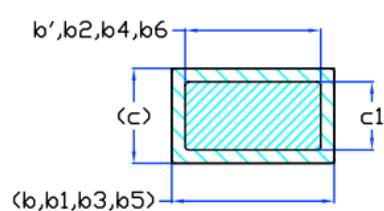


Fig. 26 Safe Operating Area

Package Dimensions



Dimensions In Millimeters		
SYMBOL	MIN.	MAX.
A	4.83	5.21
A1	2.29	2.54
A2	1.91	2.16
b	1.07	1.33
b'	1.07	1.28
b1	2.39	2.94
b2	2.39	2.84
b3	1.07	1.60
b4	1.07	1.50
b5	2.39	2.69
b6	2.39	2.64
c	0.55	0.68
c1	0.55	0.65
D	23.30	23.60
D1	16.25	17.65
D2	0.95	1.25
E	15.75	16.13
E1	13.10	14.15
E2	3.68	5.10
E3	1.00	1.90
E4	12.38	13.43
e	2.54 BSC	
e1	5.08 BSC	
L	17.31	17.82
L1	3.97	4.37
L2	2.35	2.65
N	4	
ø P	3.51	3.65
ø P1	7.18 REF.	
Q	5.49	6
S	6.04	6.3



Recommended Solder Pad Layout

Section F--F, G--G, H--H

Note:

1. Package Reference: JEDEC TO247, Variation AD
2. All Dimensions are in mm
3. Slot Required, Notch May Be Rounded
4. Dimension D&E Do Not Include Mold Flash
5. Subject to Change Without Notice